

Application/Control No.	Applicant(s)/Patent under Reexamination
09/674,079	MERIC ET AL.
Examiner	Art Unit
Hai Tran	2611

SEARCHED							
Class	Subclass	Date	Examiner				
345	530-574	5709/05	HUT				

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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